Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/617,172	KIM ET AL.		
Examiner	Art Unit		
Tianije Chen	2627		

SEARCHED				
Class	Subclass	Date	Examiner	
Updated		6/15/2006	TJ	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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